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PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Alain BETHUNE Group Art Unit: 1734

Application No.: 09/688,961 Examiner: S. PURVIS

Filed: October 17, 2000 Docket No.: 107615

For: METHOD OF HOT MARKING, AND A MULTILAYER STRUCTURE FOR

IMPLEMENTING SUCH A METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits after the filing of a Request for Continued Examination under 37 CFR §1.114. No certification or fee is required.
- 3. An English language Abstract of the non-English language reference is attached hereto.

4. A computer-generated English language translation of the Japanese Patent Publication has been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and is attached, but has not been reviewed for accuracy.

Respectfully submitted,

Leana Livn

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WPB:LL/tlp

Date: January 13, 2006

OLIFF & BERRIDGE, PLC P.O. Box 19928 Alexandria, Virginia 22320 Telephone: (703) 836-6400 DEPOSIT ACCOUNT USE
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Form PTO-1449 (REV. 8-83)				ATTY DOCKET NO. 107615			APPLICATION NO. 09/688,961		
JAN 1 3 2006 U.S. PA				APPLICANT(S) Alain BETHUNE					
				FILING DATE October 17, 2000			GROUP 1734		
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	1.	JP-A 9-78473 (with English abstract and machine translation)	03-25-1997	' Japan					
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conformance and not considered. Include copy of this form with next communication to applicant.									

Date: January 13, 2006